



ALPHA & OMEGA
SEMICONDUCTOR

AOSX32128

20V N-Channel MOSFET

General Description

- Trench Power MOSFET technology
- Low $R_{DS(ON)}$
- Low Gate Charge
- RoHS 2.0 and Halogen-Free Compliant

Product Summary

V_{DS}	20V
I_D (at $V_{GS}=10V$)	3.2A
$R_{DS(ON)}$ (at $V_{GS}=4.5V$)	< 75mΩ
$R_{DS(ON)}$ (at $V_{GS}=2.5V$)	< 90mΩ
$R_{DS(ON)}$ (at $V_{GS}=1.8V$)	< 120mΩ

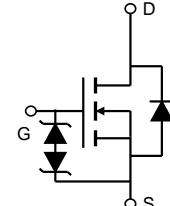
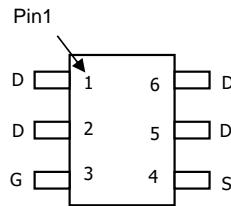
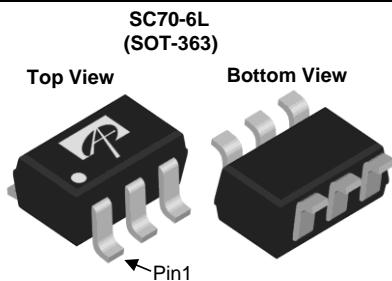
Applications

- This device is ideal for Load Switch

Typical ESD protection

100% R_g Tested

HBM Class 2



Orderable Part Number	Package Type	Form	Minimum Order Quantity
AOSX32128	SC70-3	Tape & Reel	3000

Absolute Maximum Ratings $T_A=25^\circ C$ unless otherwise noted

Parameter	Symbol	Maximum		Units
Drain-Source Voltage	V_{DS}	20		V
Gate-Source Voltage	V_{GS}	± 8		V
Continuous Drain Current	I_D	3.2		A
$T_A=70^\circ C$		2.5		
Pulsed Drain Current	I_{DM}	13		
Power Dissipation ^B	P_D	1.1		W
$T_A=25^\circ C$		0.7		
Power Dissipation ^B	$T_A=70^\circ C$			
Junction and Storage Temperature Range	T_J, T_{STG}	-55 to 150		°C

Thermal Characteristics

Parameter	Symbol	Typ	Max	Units
Maximum Junction-to-Ambient ^A	R_{JJA}	90	110	°C/W
$t \leq 10s$		110	135	°C/W
Maximum Junction-to-Ambient ^{A,D}	Steady-State			
Maximum Junction-to-Lead	R_{JL}	60	72	°C/W
	Steady-State			

Electrical Characteristics ($T_J=25^\circ\text{C}$ unless otherwise noted)

Symbol	Parameter	Conditions	Min	Typ	Max	Units
STATIC PARAMETERS						
BV_{DSS}	Drain-Source Breakdown Voltage	$I_D=250\mu\text{A}, V_{GS}=0\text{V}$	20			V
I_{DSS}	Zero Gate Voltage Drain Current	$V_{DS}=20\text{V}, V_{GS}=0\text{V}$ $T_J=55^\circ\text{C}$		1	5	μA
I_{GSS}	Gate-Body leakage current	$V_{DS}=0\text{V}, V_{GS}=\pm 8\text{V}$			± 10	μA
$V_{GS(\text{th})}$	Gate Threshold Voltage	$V_{DS}=V_{GS}, I_D=250\mu\text{A}$	0.4	0.85	1.3	V
$R_{DS(\text{ON})}$	Static Drain-Source On-Resistance	$V_{GS}=4.5\text{V}, I_D=3.2\text{A}$ $T_J=125^\circ\text{C}$		55	75	$\text{m}\Omega$
		$V_{GS}=2.5\text{V}, I_D=3\text{A}$		75	102	
		$V_{GS}=1.8\text{V}, I_D=1\text{A}$		66	90	
g_{FS}	Forward Transconductance	$V_{DS}=5\text{V}, I_D=3.2\text{A}$		86	120	$\text{m}\Omega$
V_{SD}	Diode Forward Voltage	$I_S=1\text{A}, V_{GS}=0\text{V}$		0.75	1	V
I_S	Maximum Body-Diode Continuous Current				1.5	A
DYNAMIC PARAMETERS						
C_{iss}	Input Capacitance	$V_{GS}=0\text{V}, V_{DS}=10\text{V}, f=1\text{MHz}$		190		pF
C_{oss}	Output Capacitance			30		pF
C_{rss}	Reverse Transfer Capacitance			23		pF
R_g	Gate resistance	$f=1\text{MHz}$	4	8	12	Ω
SWITCHING PARAMETERS						
$Q_g(4.5\text{V})$	Total Gate Charge	$V_{GS}=4.5\text{V}, V_{DS}=10\text{V}, I_D=3.2\text{A}$		2.2	6	nC
Q_{gs}	Gate Source Charge			0.2		nC
Q_{gd}	Gate Drain Charge			0.6		nC
$t_{D(\text{on})}$	Turn-On Delay Time	$V_{GS}=4.5\text{V}, V_{DS}=10\text{V}, R_L=3.12\Omega, R_{\text{GEN}}=3\Omega$		5.5		ns
t_r	Turn-On Rise Time			6		ns
$t_{D(\text{off})}$	Turn-Off Delay Time			21.5		ns
t_f	Turn-Off Fall Time			5		ns
t_{rr}	Body Diode Reverse Recovery Time	$I_F=3.2\text{A}, di/dt=300\text{A}/\mu\text{s}$		3.7		ns
Q_{rr}	Body Diode Reverse Recovery Charge	$I_F=3.2\text{A}, di/dt=300\text{A}/\mu\text{s}$		1.7		nC

A. The value of R_{JJA} is measured with the device mounted on 1in² FR-4 board with 2oz. Copper, in a still air environment with $T_A=25^\circ\text{C}$. The value in any given application depends on the user's specific board design.

B. The power dissipation P_D is based on $T_{J(\text{MAX})}=150^\circ\text{C}$, using $\leq 10\text{s}$ junction-to-ambient thermal resistance.

C. Repetitive rating, pulse width limited by junction temperature $T_{J(\text{MAX})}=150^\circ\text{C}$. Ratings are based on low frequency and duty cycles to keep initial $T_J=25^\circ\text{C}$.

D. The R_{JJA} is the sum of the thermal impedance from junction to lead $R_{J JL}$ and lead to ambient.

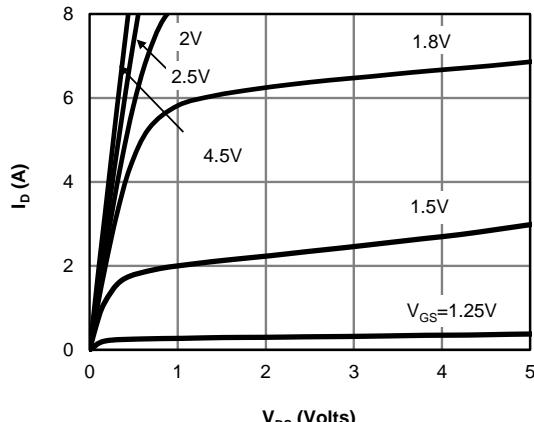
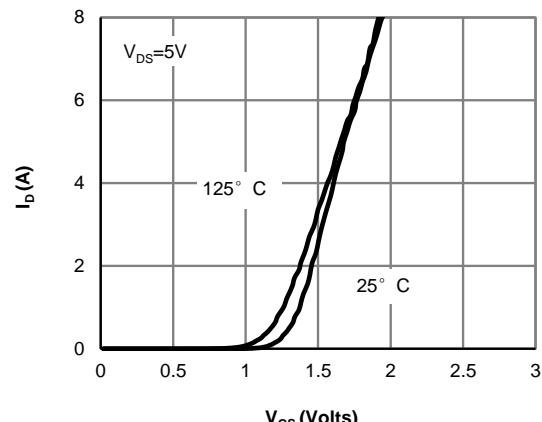
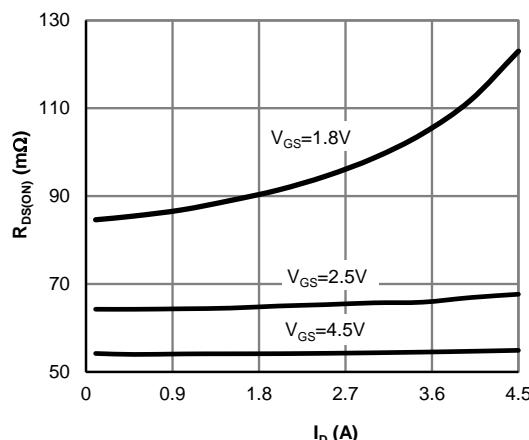
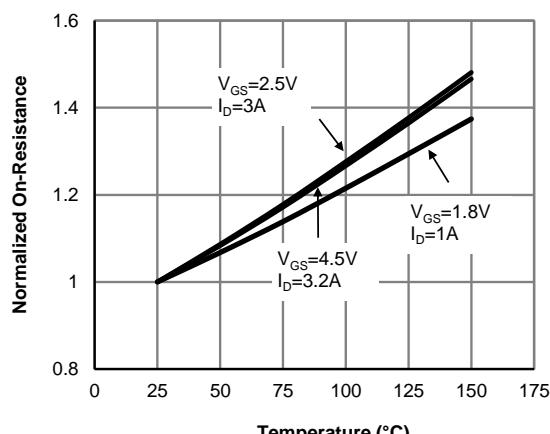
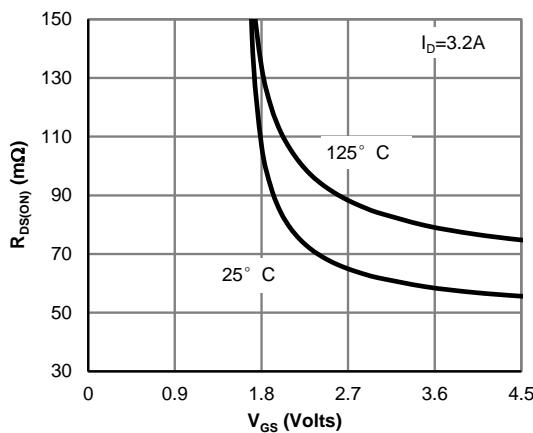
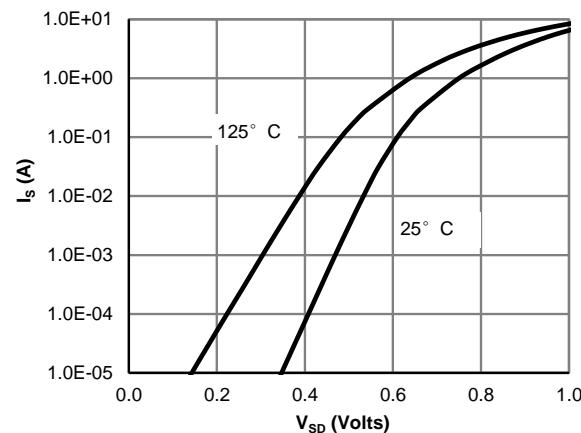
E. The static characteristics in Figures 1 to 6 are obtained using $<300\mu\text{s}$ pulses, duty cycle 0.5% max.

F. These curves are based on the junction-to-ambient thermal impedance which is measured with the device mounted on 1in² FR-4 board with 2oz. Copper, assuming a maximum junction temperature of $T_{J(\text{MAX})}=150^\circ\text{C}$. The SOA curve provides a single pulse rating.

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TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS

Figure 1: On-Region Characteristics (Note E)

Figure 2: Transfer Characteristics (Note E)

Figure 3: On-Resistance vs. Drain Current and Gate Voltage (Note E)

Figure 4: On-Resistance vs. Junction Temperature (Note E)

Figure 5: On-Resistance vs. Gate-Source Voltage (Note E)

Figure 6: Body-Diode Characteristics (Note E)

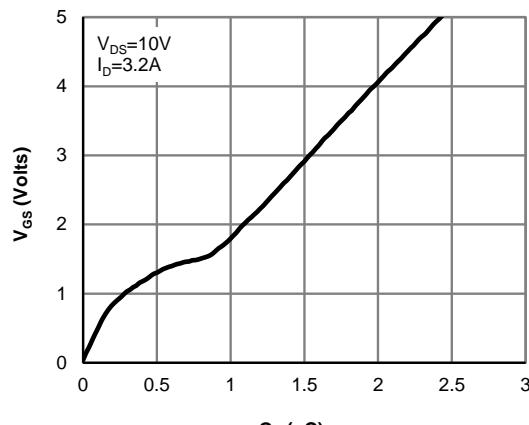
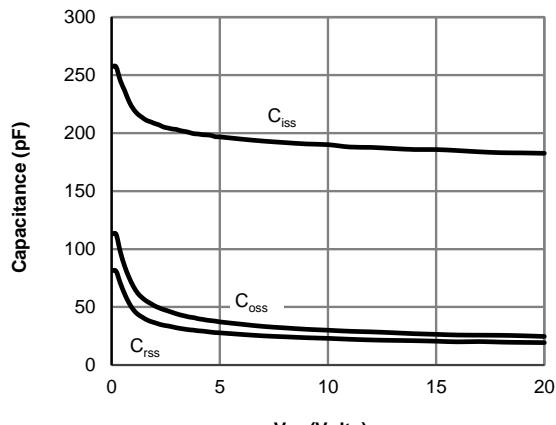
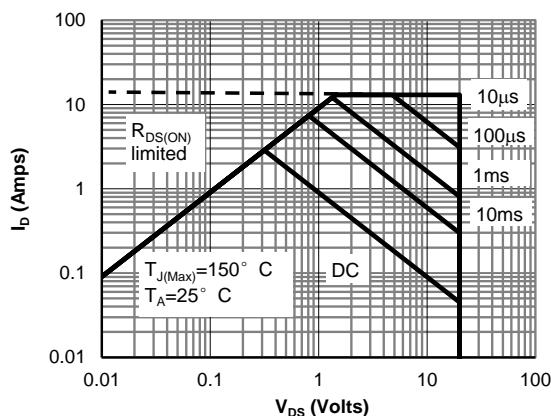
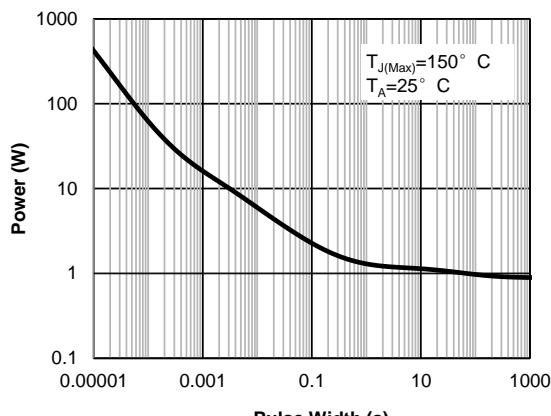
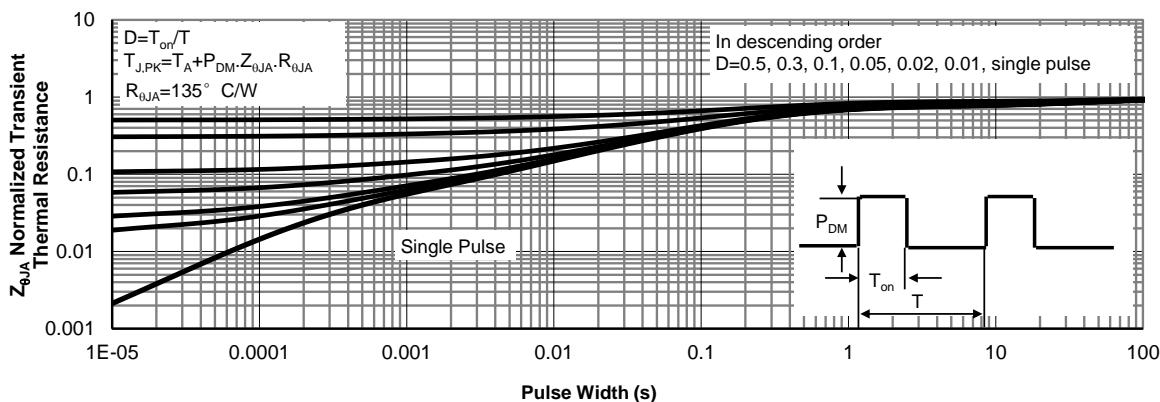
TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS

Figure 7: Gate-Charge Characteristics

Figure 8: Capacitance Characteristics

Figure 9: Maximum Forward Biased Safe Operating Area (Note F)

Figure 10: Single Pulse Power Rating Junction-to-Ambient (Note F)

Figure 11: Normalized Maximum Transient Thermal Impedance (Note F)

Figure A: Gate Charge Test Circuit & Waveforms

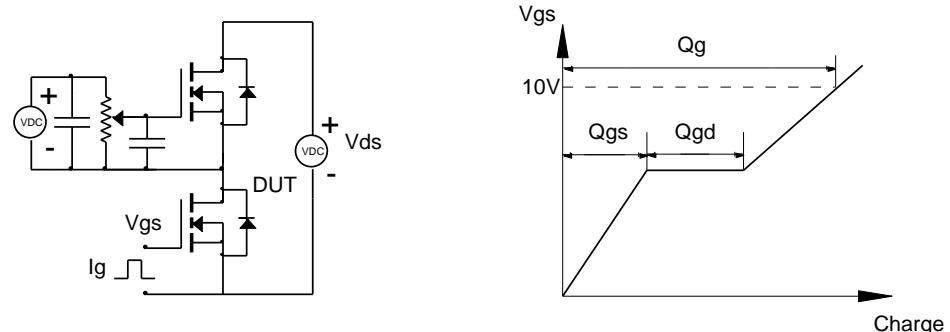


Figure B: Resistive Switching Test Circuit & Waveforms

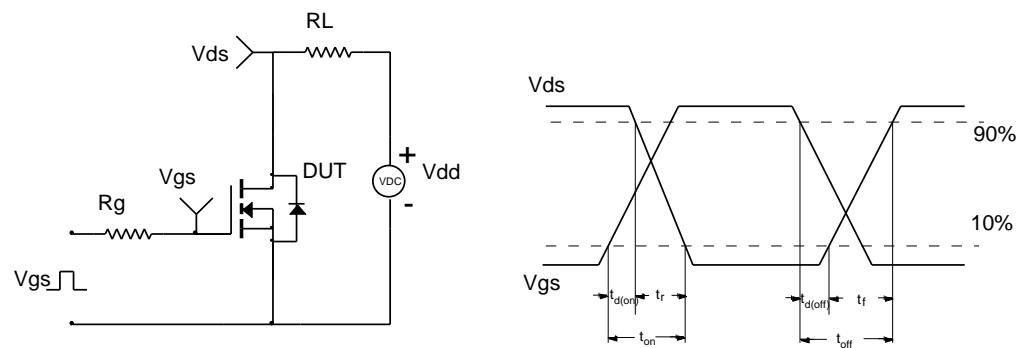


Figure C: Unclamped Inductive Switching (UIS) Test Circuit & Waveforms

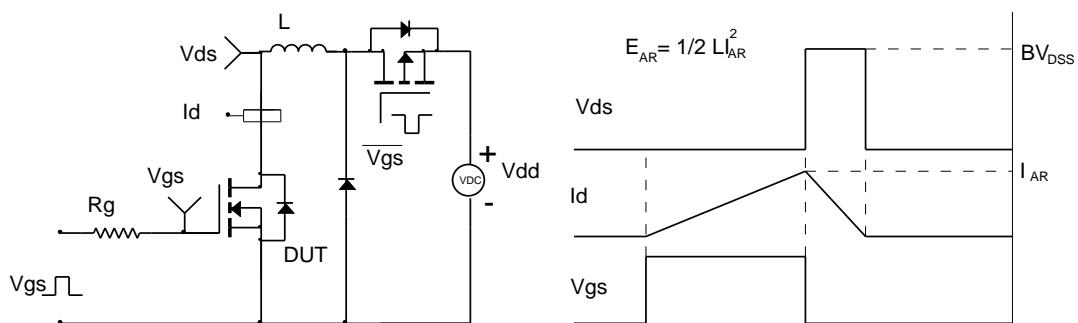


Figure D: Diode Recovery Test Circuit & Waveforms

